## FPA-5550iZ2 i-line Stepper for Logic, Memory & Photonics Applications



#### FPA-5550iZ2 Features

- Resolution ≤ 350 nm
- Throughput ≥ 230 wafers per hour\* for 200 or
- · 300 mm wafers
- Shot-Shape Compensator (SSC) Unit improves overlay matching accuracy by adjusting intrafield magnification and skew of each shot
- Canon Built-In Metrology (CANOMAP)

### **Key Options**

- Off-Axis Scope 2 (OAS2) Infrared (IR) Alignment scope for Color Filter (CF) & Backside Illuminated (BSI) applications
- Oxygen Concentration Control System (OCCS)
- Reticle Thermal Expansion Comp. (RTEC)
- Die-by-Die Overlay Compensation (EAGA)
- 200, 300 mm wafer handling
- Pellicle Particle Checker
- PC Remote Console
- · GEM-compliant Online Software

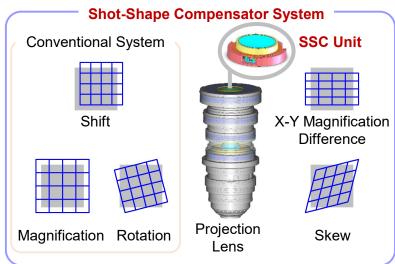
	w/out Compensation	EAGA	EAGA with SSC
Overlay Error 3σ [nm]			
Х	99.1	37.0	22.7
Y	93.4	42.5	19.5

FPA-5550iZ2 steppers can reduce overlay error using optional shot-by-shot overlay (EAGA) and SSC options

# High-Productivity and High-Overlay Accuracy i-line Stepper for Low-CoO Fabrication

FPA-5550iZ2 i-line Steppers offer a low cost Mix-&-Match lithography solution for Logic, Memory, advanced packaging, CMOS Image Sensor (CIS) fabrication and support the growing demand for Internet-of-Things (IoT) device fabrication on both 200 and 300 mm wafers.

FPA-5550iZ2 Steppers offers a balance between productivity and alignment accuracy. Throughput upgrade options include calibration, alignment, exposure & wafer transfer sequence optimization, and reduced wafer lot exchange times. Overlay matching can also be improved through shot-specific intra-field compensation options.



Shot-Shape Compensator (SSC) Unit compensates for intra-field X & Y Mag and Skew differences

FPA-5550iZ2 Specifications					
Technology	i-line Stepper (365 nm)				
Resolution	≤ 350 nm (≤ 280 nm @ 2/3 Annular)				
Throughput	≥ 230 wph				
Single Machine Overlay	≤ 18 nm (Front)				
Numerical Aperture	0.45 – 0.57				
Lens Reduction Ratio	4:1				
Exposure Field	26 x 33 mm				
Substrate Size Options*	200, 300 mm				
Dimensions (W x D x H)	2.3 x 3.66 x 3.0 m				

<sup>\* =</sup> Options Required

## **Canon Lithography System Lineup**

Canon Photolithography equipment is designed to help provide exceptional quality, performance, and cost of ownership for your wafer imaging applications.

Canon FPA (Fine Pattern Aligner) Series Nanoimprint, i-line and Deep Ultraviolet (DUV) lithography systems are used in the fabrication and heterogeneous integration of high-tech devices including integrated circuits, hard disk read/write heads, microelectromechanical systems (MEMS) devices, image sensors, displays, power devices and light emitting diodes (LED).

Litho Product	Technology	Resolution	Lens Reduction Field Size [mm]	Substrate Options [mm]
FPA-6300ES6a	KrF (248 nm) Scanner	≤ 100 nm (≤ 90 nm 2/3 Ann)	4:1 26 x 33	200 300
FPA-6300ESW	KrF (248 nm) Scanner	≤ 130 nm	3.125:1 33 x 42.2	200 300
FPA-5550iZ2	i-line (365 nm) Stepper	≤ 350 nm (≤ 280 nm 2/3 Ann)	4:1 26 x 33	200 300
FPA-5520iV LF2	i-line (365 nm) Stepper	≤ 0.8 µm	2:1 52 x 68	300
FPA-5510iX	i-line (365 nm) Stepper	≤ 0.5 µm	2:1 50 x 50	300
FPA-8000iW	i-line (365 nm) Panel Stepper	≤ 0.8 µm	2:1 52 x 68	515 x 515 (panels)
FPA-3030EX6	KrF (248 nm) Stepper	≤ 150 nm	5:1 22 x 22	50, 75, 100, 125, 150, 200
FPA-3030i5a	i-line (365 nm) Stepper	≤ 350 nm	5:1 22 x 22	50, 75, 100, 125, 150, 200
FPA-3030iWa	i-line (365 nm) Stepper	≤ 0.8 µm	2:1 52 x 52	50, 75, 100, 125, 150, 200
FPA-1200NZ2C	Nanoimprint Lithography	≤ 15 nm	1:1 26 x 33	200 300
MS-001	Wafer Overlay Metrology System			300

All options may not be available on all models. Contact Canon for details 
\* = Options Required

### **Canon USA**

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